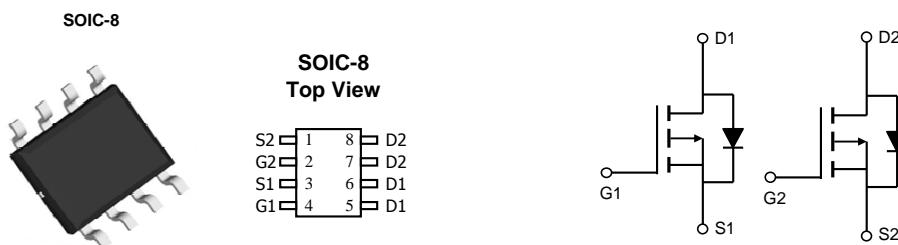


## General Description

The AO4801A combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is suitable for use as a load switch or in PWM applications.

## Features

$V_{DS}$	-30V
$I_D$ (at $V_{GS}=-10V$ )	-5A
$R_{DS(ON)}$ (at $V_{GS}=-10V$ )	< 48mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$ )	< 57mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$ )	< 80mΩ



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-5	A
Current <sup>B</sup>		-4	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-28	
Avalanche Current <sup>C</sup>	$I_{AS}, I_{AR}$	17	A
Avalanche energy L=0.1mH <sup>C</sup>	$E_{AS}, E_{AR}$	14	mJ
Power Dissipation <sup>B</sup>	$P_D$	2	W
Power Dissipation <sup>B</sup>		1.3	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \le 10\text{s}$	$R_{\theta JA}$	48	62.5	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		74	90	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	32	40	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$ , $V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}$ , $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}$ , $V_{GS}=\pm 12\text{V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=-250\mu\text{A}$	-0.5	-0.9	-1.3	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-4.5\text{V}$ , $V_{DS}=-5\text{V}$	-28			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}$ , $I_D=-5\text{A}$ $T_J=125^\circ\text{C}$		40 60	48	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}$ , $I_D=-3.5\text{A}$			45	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}$ , $I_D=-2.5\text{A}$			60	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=-5\text{V}$ , $I_D=-5\text{A}$		18		S
$V_{SD}$	Diode Forward Voltage	$I_S=-1\text{A}$ , $V_{GS}=0\text{V}$		-0.7	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-2.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}$ , $V_{DS}=-15\text{V}$ , $f=1\text{MHz}$	515	645	780	pF
$C_{oss}$	Output Capacitance		55	80	105	pF
$C_{rss}$	Reverse Transfer Capacitance		30	55	80	pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}$ , $V_{DS}=0\text{V}$ , $f=1\text{MHz}$	4	7.8	12	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=-4.5\text{V}$ , $V_{DS}=-15\text{V}$ , $I_D=-5\text{A}$	5	7	9	nC
$Q_{gs}$	Gate Source Charge			1.5		nC
$Q_{gd}$	Gate Drain Charge			2.5		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-10\text{V}$ , $V_{DS}=-15\text{V}$ , $R_L=3\Omega$ , $R_{\text{GEN}}=6\Omega$		6.5		ns
$t_r$	Turn-On Rise Time			3.5		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			41		ns
$t_f$	Turn-Off Fall Time			9		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=-5\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		11	15	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=-5\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$		3.5	5	nC

A. The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{QUL}}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

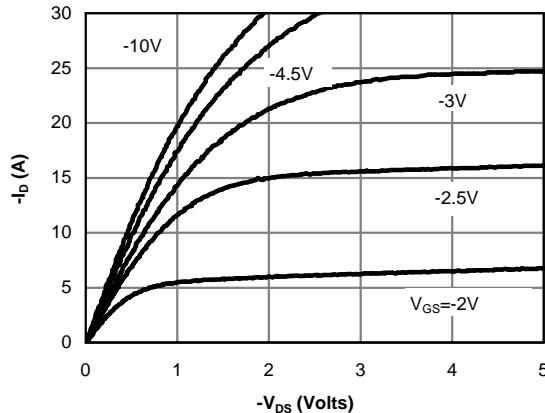
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Fig 1: On-Region Characteristics (Note E)

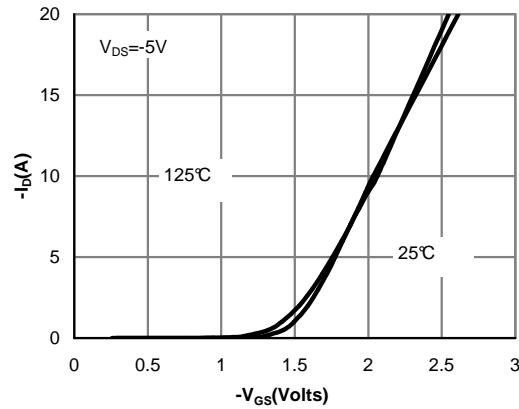


Figure 2: Transfer Characteristics (Note E)

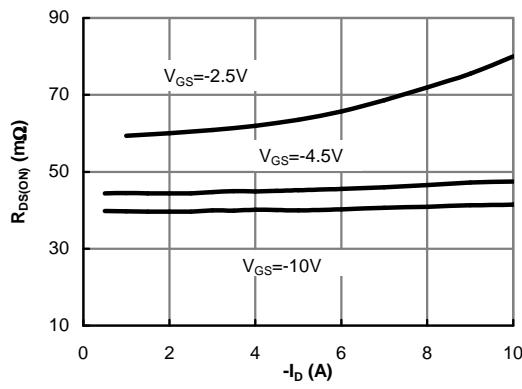


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

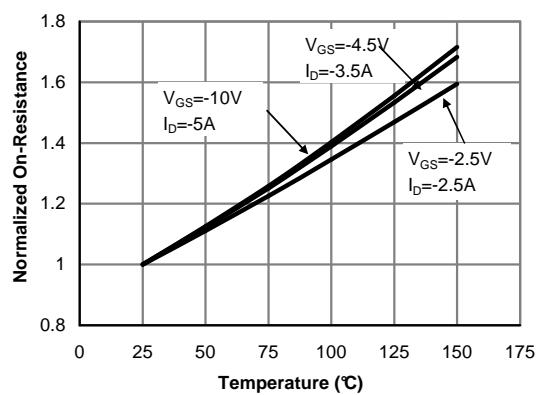


Figure 4: On-Resistance vs. Junction Temperature (Note E)

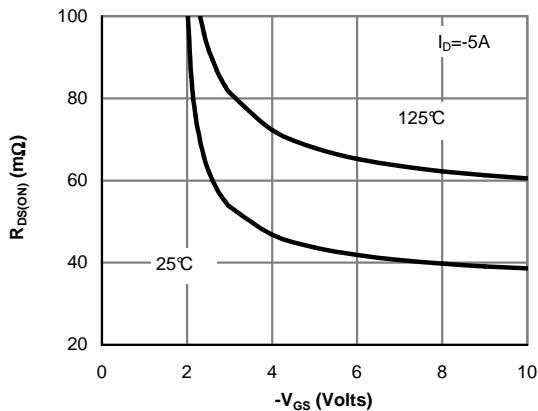


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

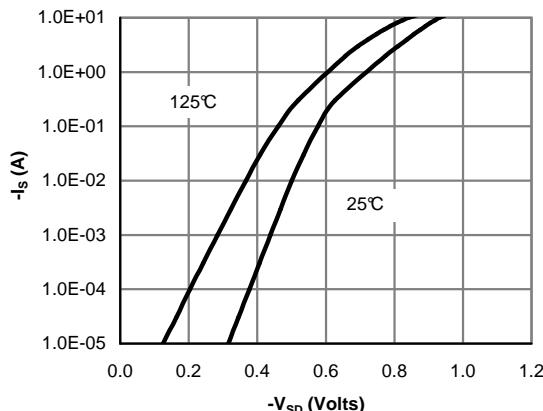
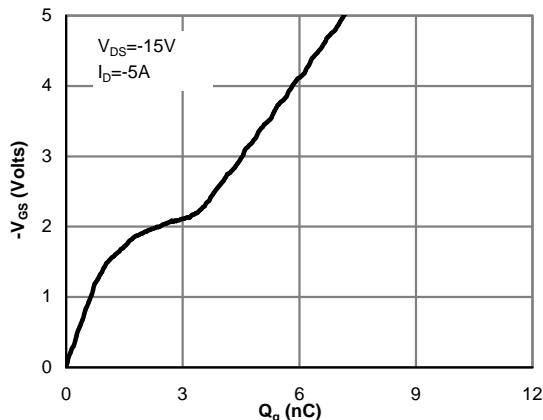
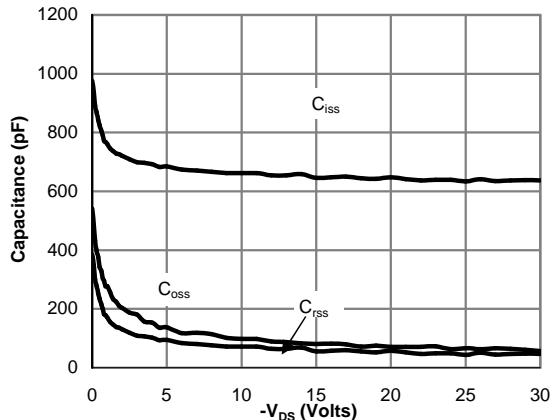
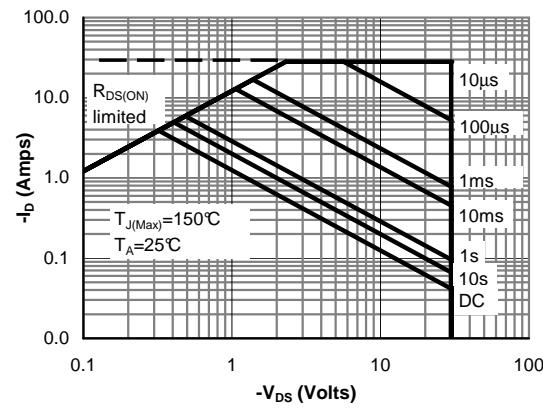
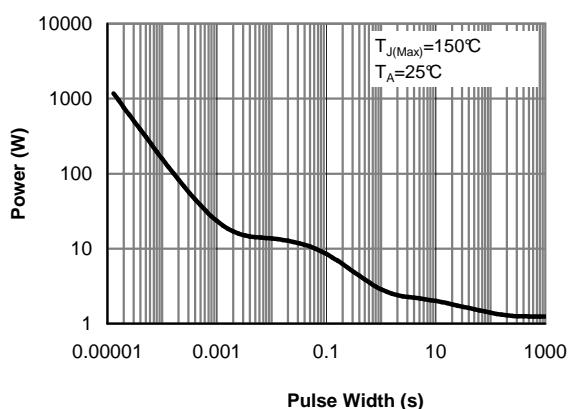
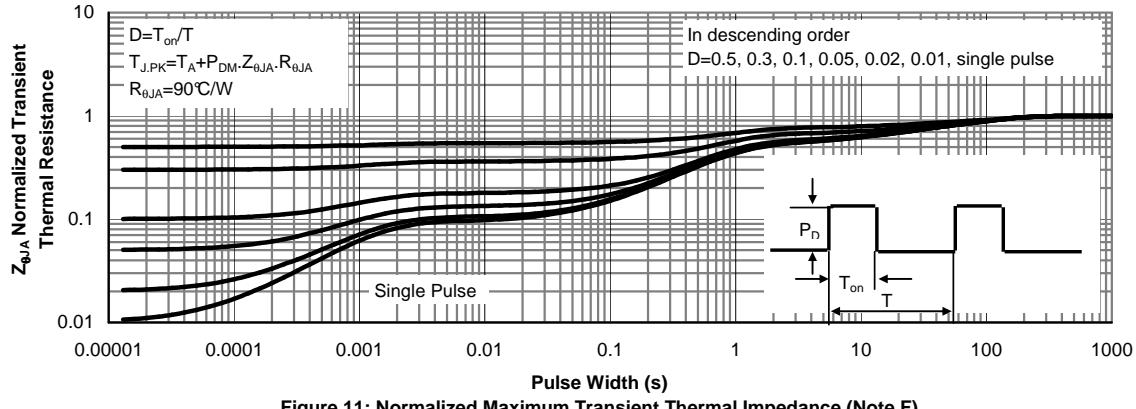
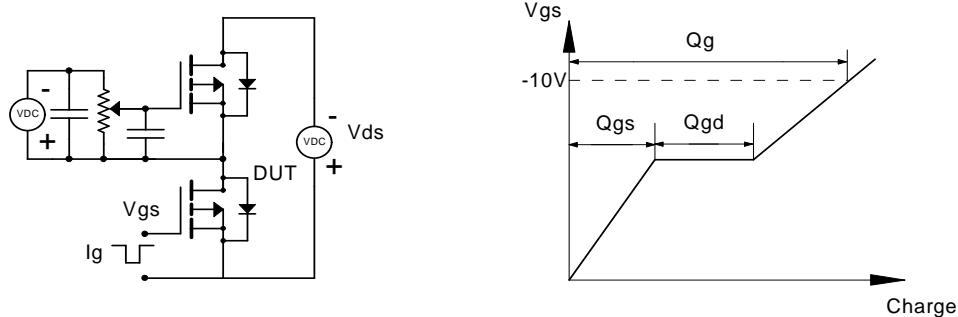
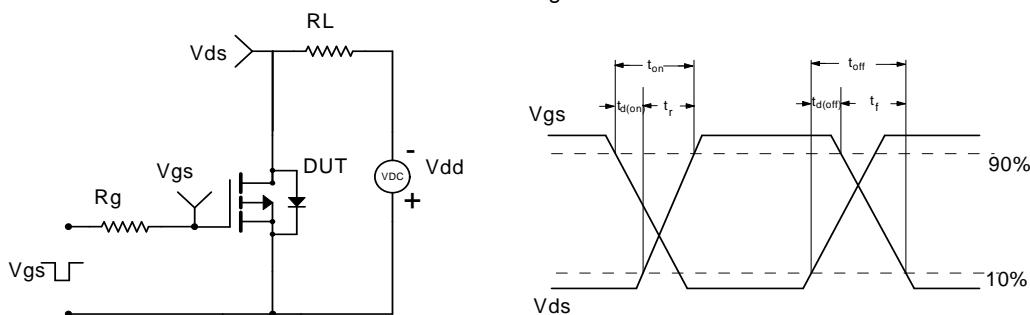
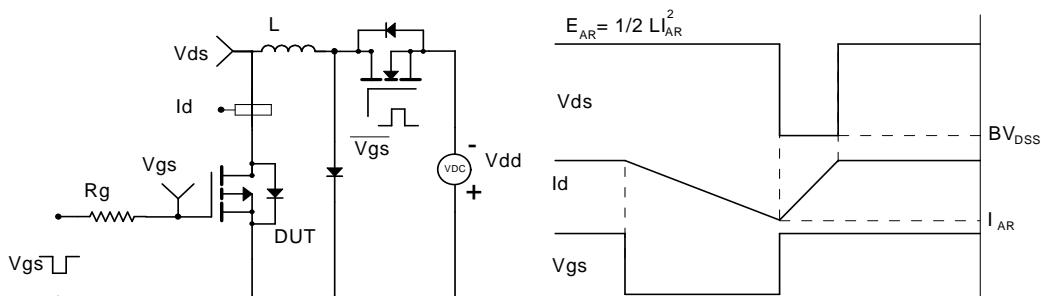


Figure 6: Body-Diode Characteristics (Note E)

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
